

Oral Programme MC8

Modeling diffraction effects from layered systems and nanomaterials

Convener: David L. Bish

Wednesday 17 June, 2009

Chair: David L. Bish

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| 08.50 – 09.20 | MC8.Wed.KL1
<i>Matteo Leoni*</i>
STRUCTURE/MICROSTRUCTURE ANALYSIS OF NANOCRYSTALLINE AND LAYERED SYSTEMS |
| 09.20 – 09.40 | MC8.Wed.L2
<i>Kristian Ufer*, Reinhard Kleeberg, Jörg Bergmann, Reiner Dohrmann</i>
STRUCTURALLY BASED MODELLING OF THE X-RAY DIFFRACTION PATTERNS OF ILLITE/SMECTITE MIXED LAYER MINERALS WITHIN THE RIETVELD METHOD |
| 09.40 – 10.00 | MC8.Wed.L3
<i>Hongji Yuan*, David L. Bish</i>
PARAMETRIC FITTING WITHIN THE NEWMOD ARCHITECTURE: SIMPLEX FITTING OF XRD PROFILES OF INTERSTRATIFIED PHYLLOSILICATES |
| 10.00 – 10.20 | MC8.Wed.L4
<i>P. Vishnu Kamath*</i>
POLYTYPISM AND DISORDER IN LAYERED DOUBLE HYDROXIDES |